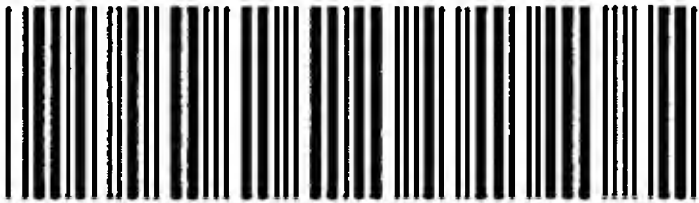


<div>Search Notes</div> <div></div>	Application/Control No.	Applicant(s)/Patent under Reexamination	
	10/003,113	SEKIGUCHI ET AL.	
	Examiner	Art Unit	
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INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
EAST Text search (USPRPUB, USPAT, EPO, JPO, DERWENT, IBM_TDB)	11/18/2005	YH
IEEE Xplore	11/5/2004	YH
ACM	11/5/2004	YH